## **AUTOMOTIVE GRADE**



# AUIRFS3004 AUIRFSL3004

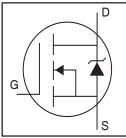
#### **Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

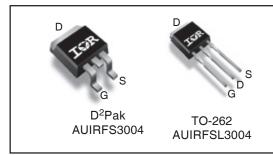
## **Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

# HEXFET® Power MOSFET



V <sub>DSS</sub>	40V
R <sub>DS(on)</sub> typ.	<b>1.4m</b> $\Omega$
max.	<b>1.75m</b> $Ω$
I <sub>D (Silicon Limited)</sub>	340A①
I <sub>D (Package Limited)</sub>	195A



G	D	S
Gate	Drain	Source

## **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T<sub>A</sub>) is 25°C, unless otherwise specified.

_	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	340①	
<sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	240①	_
<sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	195	_ A
DM	Pulsed Drain Current ②	1310	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	380	W
	Linear Derating Factor	2.5	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
dv/dt	Peak Diode Recovery 4	4.4	V/ns
AS (Thermally limited)	Single Pulse Avalanche Energy ③	300	mJ
AR	Avalanche Current ②	See Fig. 14, 15, 22a, 22b	Α
= AR	Repetitive Avalanche Energy ②		mJ
Γ <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case 9 ®		0.40	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount), D <sup>2</sup> Pak ®		40	C/VV

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/

## Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.037		V/°C	Reference to 25°C, I <sub>D</sub> = 5mA <sup>②</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		1.4	1.75	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 195A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Transconductance	1170	_		S	$V_{DS} = 10V, I_{D} = 195A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20		$V_{DS} = 40V, V_{GS} = 0V$
				250	μΑ	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	<b>π</b> Λ	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V
$R_G$	Internal Gate Resistance		2.2	_	Ω	

## Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$Q_g$	Total Gate Charge		160	240		I <sub>D</sub> = 187A
$Q_{gs}$	Gate-to-Source Charge		40		nC	V <sub>DS</sub> =20V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		68		IIC	V <sub>GS</sub> = 10V ⑤
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		92			$I_D = 187A, V_{DS} = 0V, V_{GS} = 10V$
t <sub>d(on)</sub>	Turn-On Delay Time		23			$V_{DD} = 26V$
t <sub>r</sub>	Rise Time		220			I <sub>D</sub> = 195A
t <sub>d(off)</sub>	Turn-Off Delay Time		90		ns	$R_G = 2.7\Omega$
t <sub>f</sub>	Fall Time		130			V <sub>GS</sub> = 10V ⑤
C <sub>iss</sub>	Input Capacitance		9200			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		2020			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		1340		pF	f = 1.0  MHz,  See Fig. 5
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related) ⑦		2440			$V_{GS} = 0V$ , $V_{DS} = 0V$ to 32V, See Fig. 11
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related) ®		2690			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V$

### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			340①		MOSFET symbol
	(Body Diode)			340⊕	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			1310	A	integral reverse
	(Body Diode) ②			1310		p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 195A$ , $V_{GS} = 0V$ $\bigcirc$
t <sub>rr</sub>	Reverse Recovery Time		27			$T_J = 25^{\circ}C$ $V_R = 34V$ ,
			31		ns	$T_{\rm J} = 125^{\circ}{\rm C}$ $I_{\rm F} = 195{\rm A}$
$Q_{rr}$	Reverse Recovery Charge		18		~C	$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s $\odot$
			41		nC	$T_J = 125^{\circ}C$
I <sub>RRM</sub>	Reverse Recovery Current		1.2		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 195A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- $I_{AS}$  = 195A,  $V_{GS}$  =10V. Part not recommended for use above this value.
- $\textcircled{4} \quad I_{SD} \leq 195 A, \ di/dt \leq 930 A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175 ^{\circ} C.$
- ⑤ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .
- as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ② Repetitive rating; pulse width limited by max. junction temperature. ② Coss eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}\, while \, V_{DS}\, is \, rising \, from \, 0$  to 80%  $V_{DSS}.$ 
  - ® When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

  - 1 R<sub> $\theta$ JC</sub> value shown is at time zero.

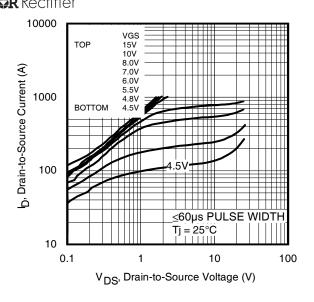


Fig 1. Typical Output Characteristics

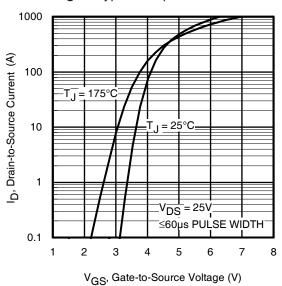
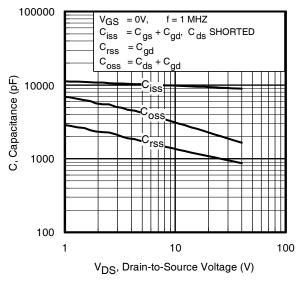


Fig 3. Typical Transfer Characteristics



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

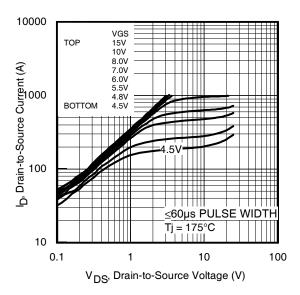


Fig 2. Typical Output Characteristics

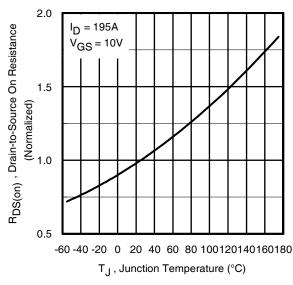


Fig 4. Normalized On-Resistance vs. Temperature

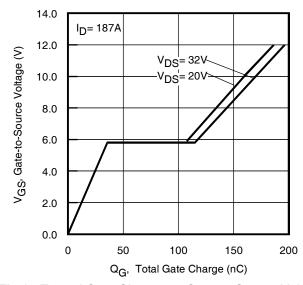
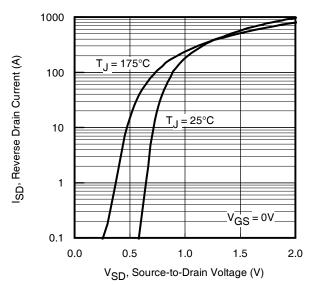
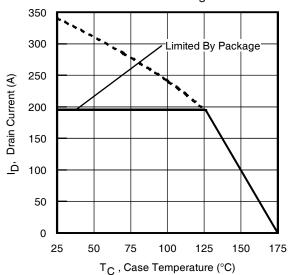


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 9.** Maximum Drain Current vs. Case Temperature

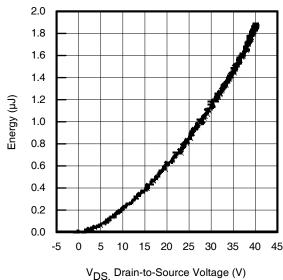


Fig 11. Typical C<sub>OSS</sub> Stored Energy

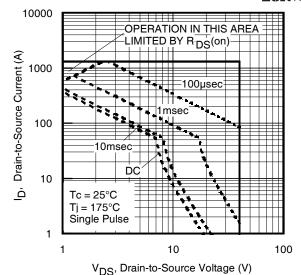


Fig 8. Maximum Safe Operating Area

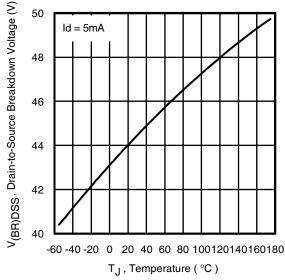


Fig 10. Drain-to-Source Breakdown Voltage

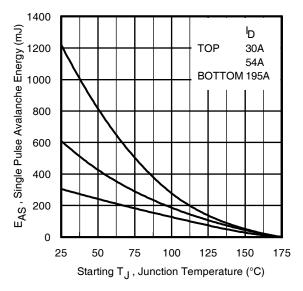


Fig 12. Maximum Avalanche Energy vs. DrainCurrent www.irf.com

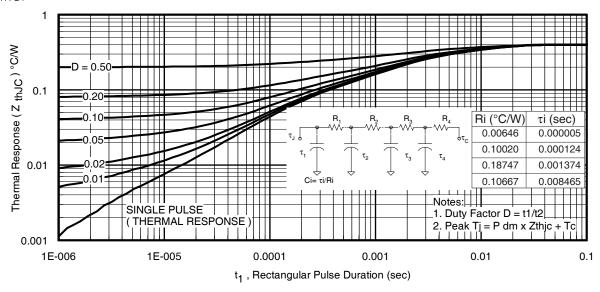


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

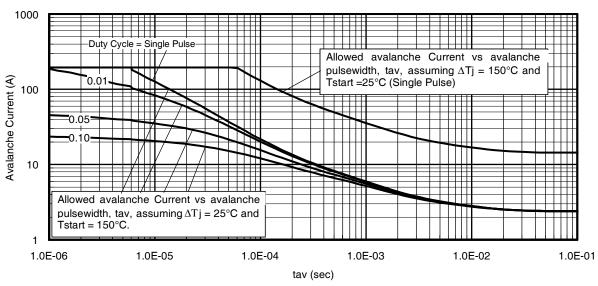


Fig 14. Typical Avalanche Current vs. Pulsewidth

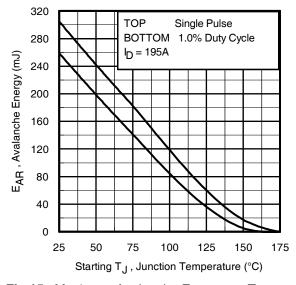


Fig 15. Maximum Avalanche Energy vs. Temperature

# Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT<sub>imax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).

t<sub>av =</sub> Average time in avalanche.

 $D = Duty cycle in avalanche = t_{av} \cdot f$ 

 $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

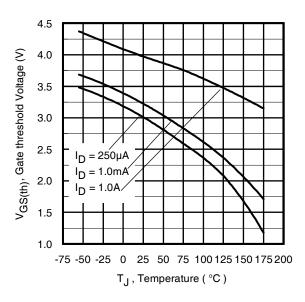


Fig 16. Threshold Voltage vs. Temperature

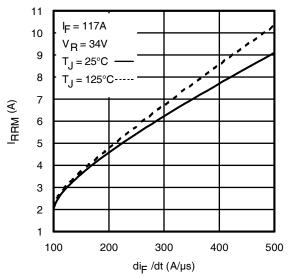


Fig. 18 - Typical Recovery Current vs. dif/dt

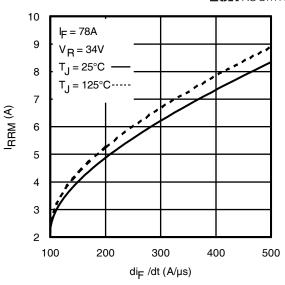


Fig. 17 - Typical Recovery Current vs. di<sub>f</sub>/dt

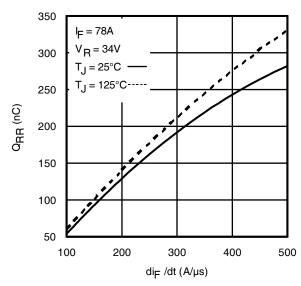


Fig. 19 - Typical Stored Charge vs. dif/dt

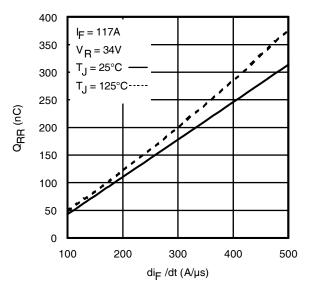


Fig. 20 - Typical Stored Charge vs. dif/dt

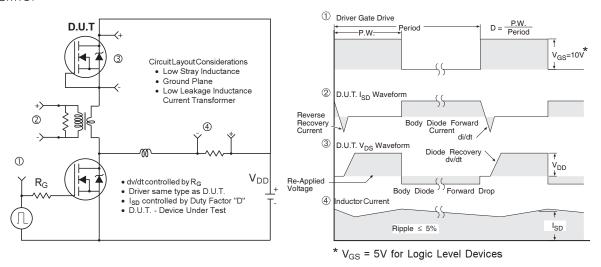


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

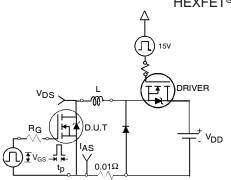


Fig 22a. Unclamped Inductive Test Circuit

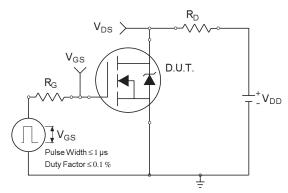


Fig 23a. Switching Time Test Circuit

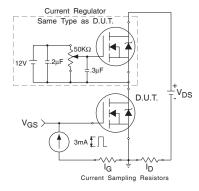


Fig 24a. Gate Charge Test Circuit

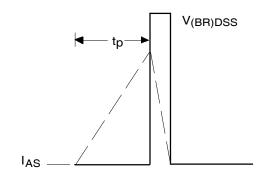


Fig 22b. Unclamped Inductive Waveforms

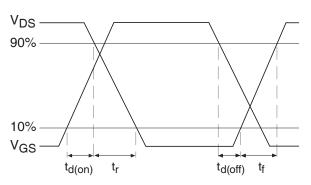


Fig 23b. Switching Time Waveforms

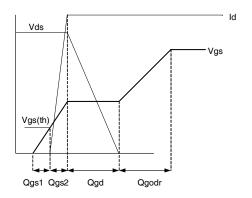
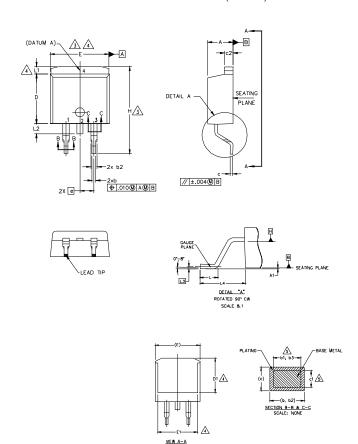


Fig 24b. Gate Charge Waveform

# D<sup>2</sup>Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S Y		Ŋ			
M B O L	MILLIM	ETERS	INC	O T E S	
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1,14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
e	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	4
L2	1,27	1.78	-	.070	
L3	0.25	BSC	.010	.010 BSC	
L4	4.78	5.28	.188	.208	

## LEAD ASSIGNMENTS

## HEXFET

1.- GATE 2, 4.- DRAIN 3.- SOURCE

#### IGBTs, CoPACK

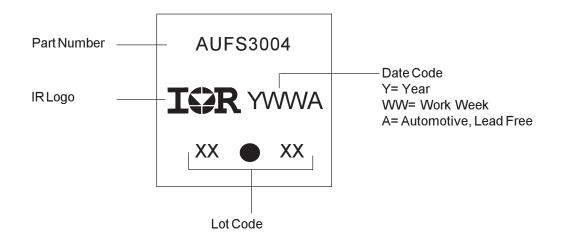
1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

#### DIODES

1.- ANODE \*
2, 4.- CATHODE
3.- ANODE

\* PART DEPENDENT.

# D<sup>2</sup>Pak Part Marking Information

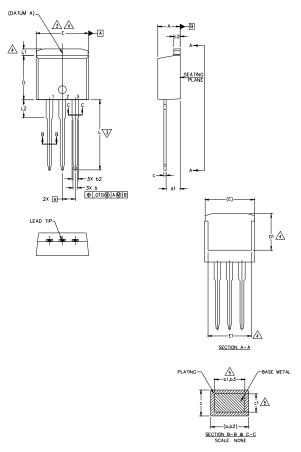


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

International IOR Rectifier

## TO-262 Package Outline

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S						
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S Y M B O L	MILLIMETERS		INC	NOTES		
L	MIN.	MAX.	MIN.	MAX.	S	
Α	4.06	4,83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1,14	1.78	.045	.070		
b3	1,14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1,14	1.65	.045	.065		
D	8,38	9,65	.330	.380	3	
D1	6.86	-	.270	-	4	
Ε	9.65	10.67	.380	.420	3,4	
E1	6.22	-	.245		4	
e	2.54	BSC	.100 BSC			
L	13,46	14,10	.530	.555		
L1	-	1.65	-	.065	4	
L2	3.56	3,71	.140	.146		

#### LEAD ASSIGNMENTS

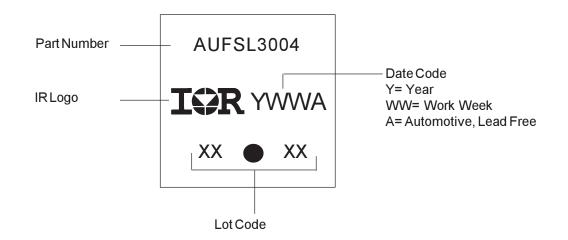
#### <u>HEXFET</u>

- 1.- GATE
- 2.- DRAIN 3.- SOURCE 4.- DRAIN

#### IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR
  3.- EMITTER
  4.- COLLECTOR

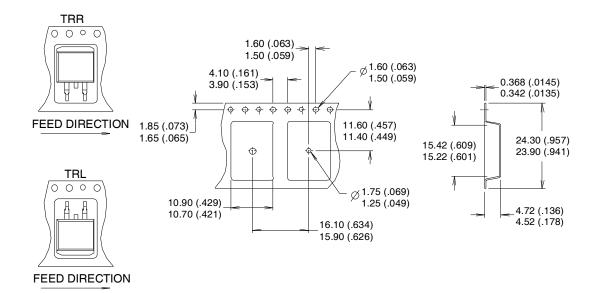
TO-262 Part Marking Information

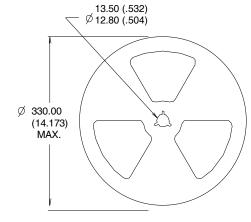


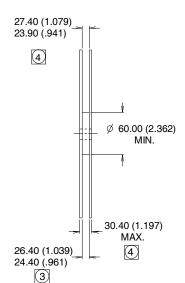
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

# D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information

Dimensions are shown in millimeters (inches)







NOTES:

- 1. COMFORMS TO EIA-418.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION MEASURED @ HUB.
- (3) (4) INCLUDES FLANGE DISTORTION @ OUTER EDGE.

10 www.irf.com **Ordering Information** 

Base part	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRFSL3004	TO-262	Tube	50	AUIRFSL3004
AUIRFS3004	D2Pak	Tube	50	AUIRFS3004
		Tape and Reel Left	800	AUIRFS3004TRL
_		Tape and Reel Right	800	AUIRFS3004TRR

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For technical support, please contact IR's Technical Assistance Center

http://www.irf.com/technical-info/

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